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## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date	Name	Classification
	<u> </u>	<del></del>	MM-YYYY		
	Α	US-2004/0086762 A1	05-2004	Maeda et al.	429/032
	В	US-2004/0137305 A1	07-2004	Inoue et al.	429/038
	С	US-			
	D	US-			
	Ę	US-			_
	F	US-			W
	G	US-			
•	Н	US-			
	-	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z	JP2003-317791	11-2003	Japan	Kayano et al.	H01M 8/24
	0					
	P					
	Q					
	R					
	s					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.